



EL979977761

Inventor: Vladimir Segal et al.

Title: Alloys Formed from Cast Materials Utilizing Equal Channel Angular Extrusion

Assignee: Honeywell International Inc.

**INFORMATION DISCLOSURE STATEMENT**

References – See Attached Form PTO-1449

The attached form PTO-1449 is submitted in compliance with 37 CFR §1.56. No admission is made regarding whether any of the submitted references is prior art. Copies of the references are attached.

Respectfully submitted,

Dated: October 22, 2003 Attorney: Jennifer J. Taylor  
Jennifer J. Taylor, Ph.D.  
Reg. No. 48,711

10/28/2003 SMINASS1 00000073 09912652

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LIST OF ART CITED BY APPLICANT  
(Use several sheets if necessary)

OCT 22 2003

APPLICANT  
Vladimir Segal et al.FILING DATE  
July 24, 2001GROUP  
1742

## U.S. PATENT DOCUMENTS

Examiner Initial		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	4,844,746	07-1989	Hormann et al.			
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						

## FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AM	62-297463	12-1987	Japan				
	AN	03-197640	08-1991	Japan				
	AO	EP0281141B2	03-1988	EPO				
	AP	59227992A	12-1984	Japan				
	AQ							

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)

	AR		V. Segal et al. "Development of a submicrometer-grained microstructure in aluminum 6061 using equal channel angular extrusion", Journal of Materials Research, Vol. 12, No. 5, pp. 1253-1261, May 1997.
	AS		ASM Handbook, Vol. 4, 1991, "Heat Treating of Aluminum Alloys", pgs. 841-879.
			Susumu Sawada, "On Advanced Sputtering Targets of Refractory Metals and Their Silicides for VLSI-Applications", 12 <sup>th</sup> International Plansee Seminar (1989) Topic 5: Ultrapure Refractory Metals, pp. 201-222.
			P. Ding et.al., "Copper Barrier, Seed Layer, and Planarization Technologies", June 10-12, 1997 VMIC Conference, pp. 87-92.
	AT		Friedman, "Grain Size Refinement in a Tantalum Ingot", Metallurgical Transactions, Vol. 2 No. 1, January 1971, pages 337-341.

EXAMINER

DATE CONSIDERED

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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